BEILSTEIN JOURNAL OF NANOTECHNOLOGY

Supporting Information

for

Atomic force acoustic microscopy reveals the influence of substrate stiffness and topography on cell behavior

Yan Liu, Li Li, Xing Chen, Ying Wang, Meng-Nan Liu, Jin Yan, Liang Cao, Lu Wang and Zuo-Bin Wang

Beilstein J. Nanotechnol. **2019,** *10,* 2329–2337. doi:10.3762/bjnano.10.223

Additional experimental data

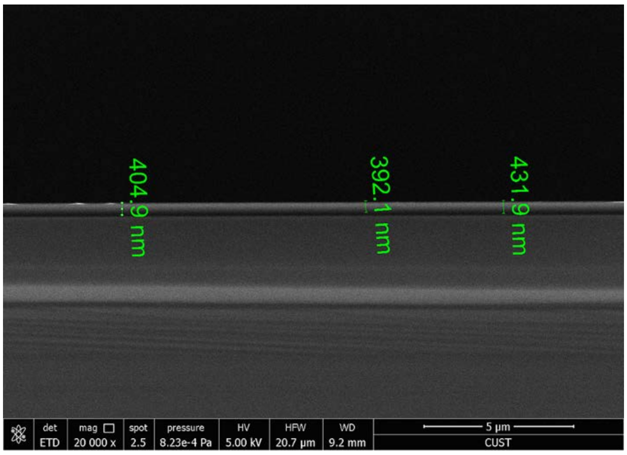

Figure S1: Coating thickness measurements of SU-8 by SEM.

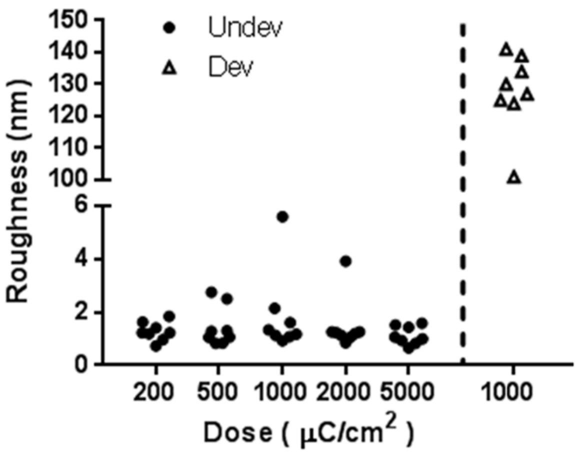

Figure S2: Surface roughness measurements of the undeveloped and the developed SU-8 film by AFAM.